

# VLSI Design Automation

張耀文

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Taipei 106, Taiwan

Spring 2004



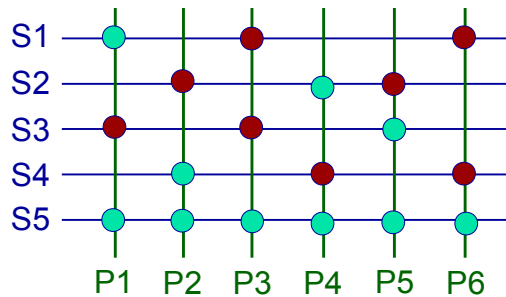
## Administrative Matters

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- **Time/Location:** Thursdays 9:10am--12:10pm; EE#2-144.
- **Instructor:** Yao-Wen Chang.
- **E-mail:** [ywchang@cc.ee.ntu.edu.tw](mailto:ywchang@cc.ee.ntu.edu.tw)
- **URL:** <http://cc.ee.ntu.edu.tw/~ywchang>.
- **Office:** EE#2-548. (Tel) 2363-5251x 548; (Fax) 2364-1972.
- **Office Hours:** Thursdays 2-3pm
- **Teaching Assistants**
  - 陳泰蓁 Tai-Chen Chen ([d0943008@ee.ntu.edu.tw](mailto:d0943008@ee.ntu.edu.tw))
  - 陳東傑 Tung-Chieh Chen ([donnie@eda.ee.ntu.edu.tw](mailto:donnie@eda.ee.ntu.edu.tw))
- **Prerequisites:** data structures (or discrete math) & logic design.
- **Required Text:** S. H. Gerez, *Algorithms for VLSI Design Automation*, John Wiley & Sons, 1999
- **References:** supplementary reading materials will be provided.

## Course Objectives

- Study techniques for electronic design automation (EDA), a.k.a. computer-aided design (CAD).
- Study IC technology evolution and their impacts on the development of EDA tools
- **Study problem-solving (-finding) techniques!!!**



## Course Contents

- Introduction to VLSI design flow/styles/automation, technology roadmap, and CMOS Technology (6 hrs)
- (Algorithmic graph theory and computational complexity)\* (2 hrs)
- (General-purpose methods for combinatorial optimization)\* (1 hr)
- Physical design: partitioning, floorplanning, placement, routing, compaction, deep submicron effects (18 hrs)
- Logic synthesis (6 hrs)
- Formal verification (6 hrs)
- Testing (6 hrs)
- Simulation (3 hrs)
- High-level synthesis (3 hrs)

## Grading Policy

- **Grading Policy:**

- Homework assignments: 25%
- One in-class open-book, open-note test: 35% (June 17)
- Programming assignment #1: 20% (due 5pm, April 23)
  - Default programming assignment #1: Any problem of the 2004 MOE IC/CAD contest
  - Contest web site: <http://www.cs.nthu.edu.tw/~cad>
  - Team work (1--4 persons) is permitted (preferably 2 persons)
- Programming assignment #2: 20% (due 5pm, June 11)
  - No team work is allowed.
- Bonus for class participation

- **Homework:** Penalty for late submission: **15% per day.**

- **WWW:**

<http://cc.ee.ntu.edu.tw/~ywchang/Courses/EDA04/eda04.html>

- **Academic Honesty:** Avoiding *cheating* at all cost.

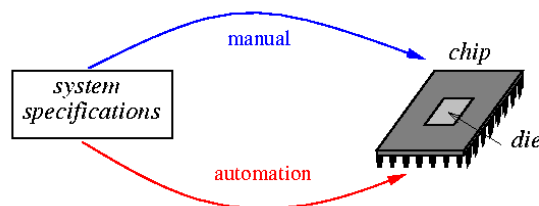
## Unit 1: Introduction

- **Course contents:**

- Introduction to VLSI design flow/methodologies/styles
- Introduction to VLSI design automation tools
- Semiconductor technology roadmap
- CMOS technology

- **Readings**

- Chapters 1-2
- Appendix A

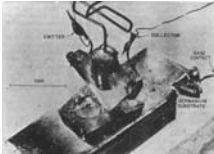


## Milestones for IC Industry

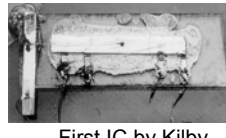
- **1947:** Bardeen, Brattain & Shockly invented the transistor, foundation of the IC industry.
- **1952:** SONY introduced the first transistor-based radio.
- **1958:** Kilby invented integrated circuits (ICs).
- **1965:** Moore's law.
- **1968:** Noyce and Moore founded Intel.
- **1970:** Intel introduced 1 K DRAM.



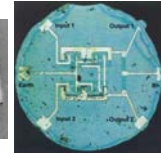
In 1956 John Bardeen, William Shockley and Walter Brattain shared the Nobel Prize in Physics for their discovery of the transistor.



First transistor



First IC by Kilby



First IC by Noyce

## Milestones for IC Industry

- **1971:** Intel announced 4-bit 4004 microprocessors (2250 transistors).
- **1976/81:** Apple II/IBM PC.
- **1984:** Xilinx invented FPGA's.
- **1985:** Intel began focusing on microprocessor products.
- **1987:** TSMC was founded (**fabless** IC design).
- **1991:** ARM introduced its first embeddable RISC IP core (**chipless** IC design).



Intel founders



4004

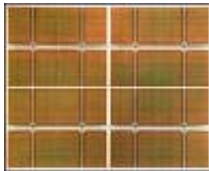


IBM PC

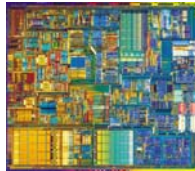


## Milestones for IC Industry (Cont'd)

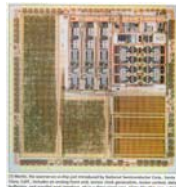
- **1996:** Samsung introduced IG DRAM.
- **1998:** IBM announces 1GHz experimental microprocessor.
- **1999/earlier:** **System-on-Chip (SOC)** applications.
- **2002/earlier:** **System-in-Package (SIP)** technology.
- An Intel P4 processor contains 42 million transistors (1 billion by 2005)
- Today, we produce > 30 million transistors per person (1 billion/person by 2008).
- **Semiconductor/IC:** #1 key field for advancing into 2000 (*Business Week*, Jan. 1995).



4GB DRAM (2001)



Pentium 4



Scanner-on-chip



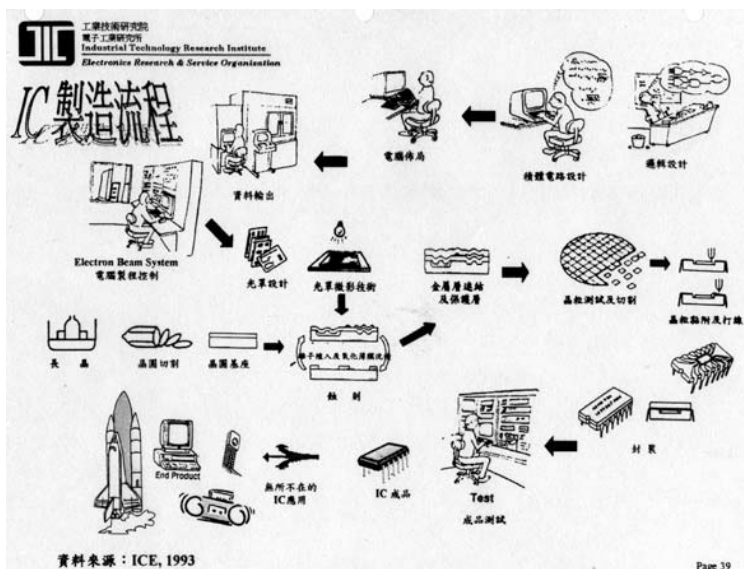
Blue tooth technology

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9

## IC Design & Manufacturing Process



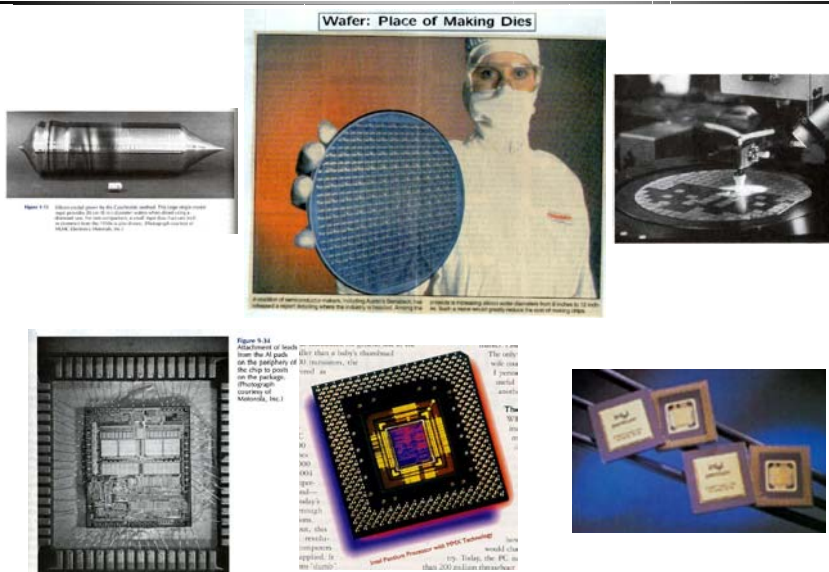
Page 39

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10

## From Wafer to Chip



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11

## Traditional VLSI Design Cycles

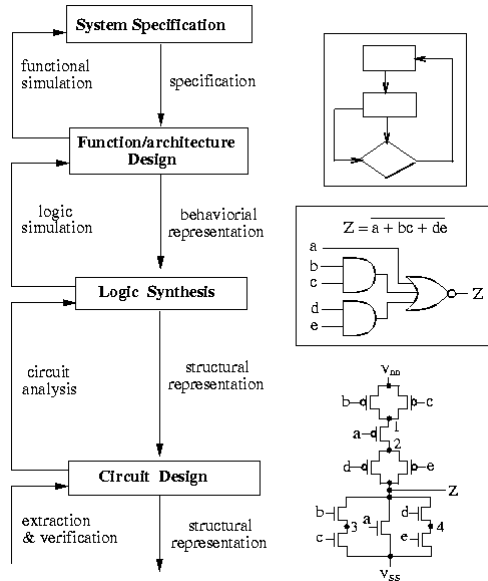
1. System specification
2. Functional design
3. Logic synthesis
4. Circuit design
5. Physical design and verification
6. Fabrication
7. Packaging
  - Other tasks involved: testing, simulation, etc.
  - Design metrics: area, speed, power dissipation, noise, design time, testability, etc.
  - Design revolution: interconnect (not gate) delay dominates circuit performance in deep submicron era.
    - Interconnects are determined in physical design.
    - Shall consider interconnections in early design stages.

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12

## Traditional VLSI Design Cycle

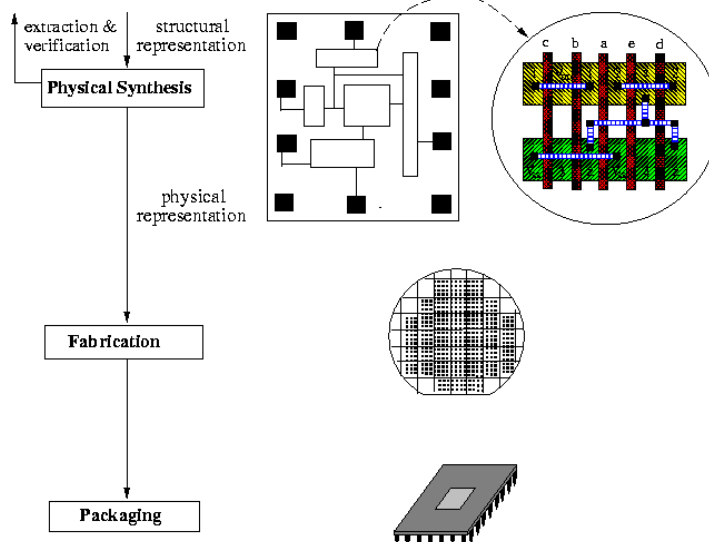


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13

## Traditional VLSI Design Flow (Cont'd)



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14

## Design Actions

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- **Synthesis:** increasing information about the design by providing more detail (e.g., logic synthesis, physical synthesis).
- **Analysis:** collecting information on the quality of the design (e.g., timing analysis).
- **Verification:** checking whether a synthesis step has left the specification intact (e.g., layout verification).
- **Optimization:** increasing the quality of the design by rearrangements in a given description (e.g., logic optimizer, timing optimizer).
- **Design Management:** storage of design data, cooperation between tools, design flow, etc. (e.g., database).

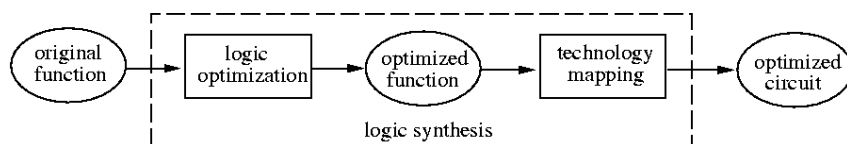
## Design Issues and Tools

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- System-level design
  - Partitioning into hardware and software, co-design, co-simulation, etc.
  - Cost estimation, design-space exploration
- Algorithmic-level design
  - Behavioral descriptions (e.g. in Verilog, VHDL)
  - High-level simulation
- From algorithms to hardware modules
  - High-level (or architectural) synthesis
- Logic design:
  - Schematic entry
  - Register-transfer level and logic synthesis
  - Gate-level simulation (functionality, power, etc)
  - Timing analysis
  - Formal verification



## Logic Design/Synthesis



- **Logic synthesis** programs transform Boolean expressions into logic gate networks in a particular library.
- Optimization goals: minimize area, delay, power, etc
- **Technology-independent** optimization: logic optimization
  - Optimizes Boolean expression equivalent.
- **Technology-dependent** optimization: **technology mapping/library binding**
  - Maps Boolean expressions into a particular cell library.

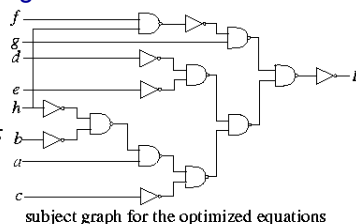
## Logic Optimization Examples

- **Two-level:** minimize the # of product terms.
  - $F = \bar{x}_1\bar{x}_2\bar{x}_3 + \bar{x}_1\bar{x}_2x_3 + x_1\bar{x}_2\bar{x}_3 + x_1\bar{x}_2x_3 + x_1x_2\bar{x}_3 \Rightarrow F = \bar{x}_2 + x_1\bar{x}_3$ .
- **Multi-level:** minimize the #'s of literals, variables.
  - E.g., equations are optimized using a smaller number of literals.

$t1 = a + b \ c;$   
 $t2 = d + e;$   
 $t3 = a \ b + d;$   
 $t4 = t1 \ t2 + fg;$   
 $t5 = t4 \ h + t2 \ t3;$   
 $F = t5;$

logic  
optimization

$t1 = d + e;$   
 $t2 = b + h;$   
 $t3 = a \ t2 + c;$   
 $t4 = t1 \ t3 + fg \ h;$



subject graph for the optimized equations

- Methods/CAD tools: Quine-McCluskey method (exponential-time exact algorithm), Espresso (heuristics for two-level logic), MIS (heuristics for multi-level logic), Synopsys, etc.

## Design Issues and Tools (Cont'd)

- Transistor-level design
  - Switch-level simulation
  - Circuit simulation
- Physical (layout) design:
  - Partitioning
  - Floorplanning and Placement
  - Routing
  - Layout editing and compaction
  - Design-rule checking
  - Layout extraction
- Design management
  - Data bases, frameworks, etc.
- **Silicon compilation:** *from algorithm to mask patterns*
  - The *idea* is approached more and more, but still far away from a single *push-button* operation

## Circuit Simulation of a CMOS Inverter (0.6 $\mu\text{m}$ )

```
M1 3 2 0 0 nch W=1.2u L=0.6u AS=2.16p PS=4.8u AD=2.16p PD=4.8u
M2 3 2 1 1 pch W=1.8u L=0.6u AS=3.24p PS=5.4u AD=3.24p PD=5.4u
CL 3 0 0.2pF
```

```
VDD 1 0 3.3
```

```
VIN 2 0 DC 0 PULSE (0 3.3 0ns 100ps 100ps 2.4ns 5ns)
```

```
.LIB '../mod_06' typical
```

```
.OPTION NOMOD POST INGOLD=2 NUMDGT=6 BRIEF
```

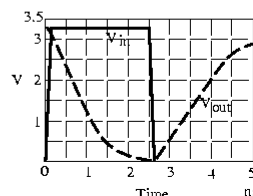
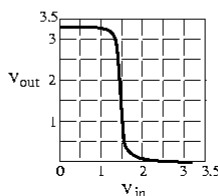
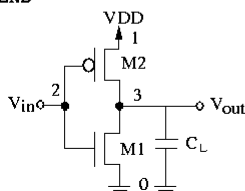
```
.DC VIN 0V 3.3V 0.001V
```

```
.PRINT DC V(3)
```

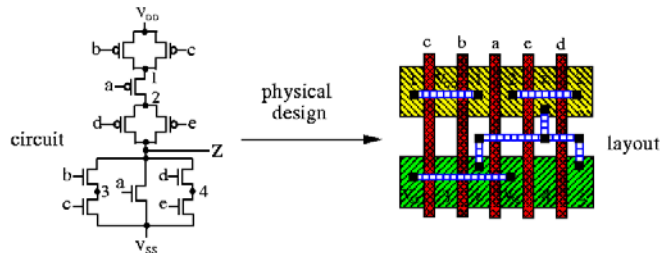
```
.TRAN 0.001N 5N
```

```
.PRINT TRAN V(2) V(3)
```

```
.END
```

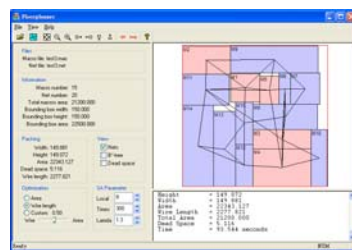
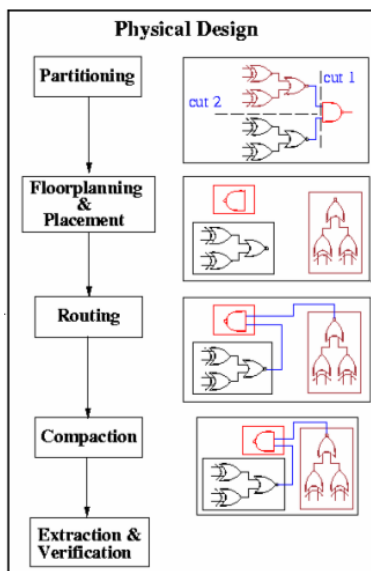


## Physical Design



- Physical design converts a circuit description into a geometric description.
- The description is used to manufacture a chip.
- Physical design cycle:
  - Logic partitioning
  - Floorplanning and placement
  - Routing
  - Compaction
- Others: circuit extraction, timing verification and design rule checking

## Physical Design Flow



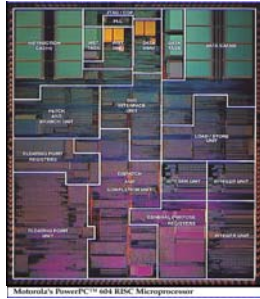
B\*-tree based floorplanning system



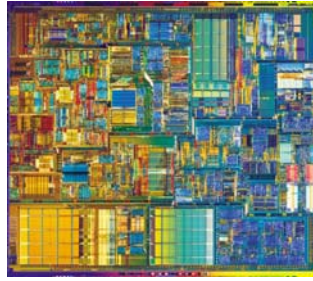
A routing system

## Floorplan Examples

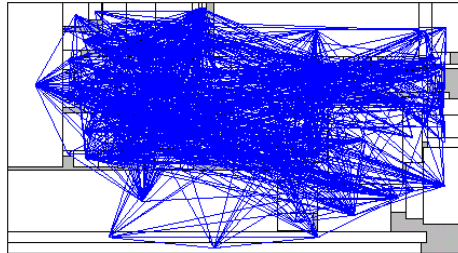
PowerPC  
604



Intel  
Pentium 4

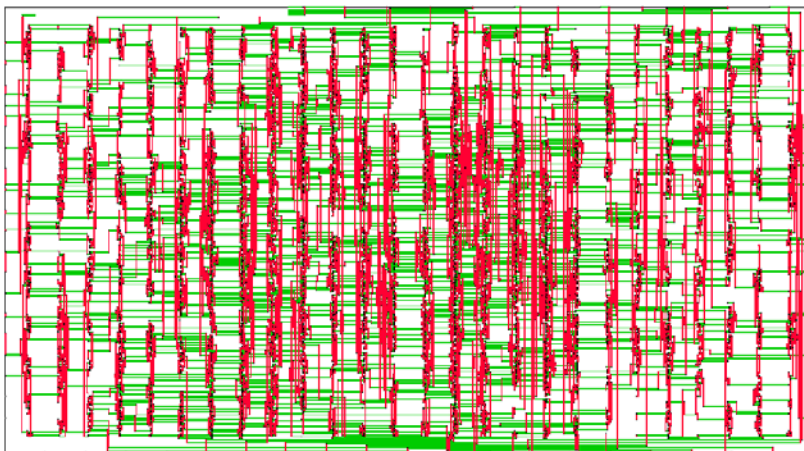


A floorplan  
with  
interconnections

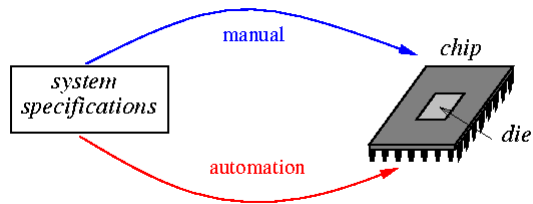


## Routing Example

- 0.18um technology, pitch = 1 um, 2774 nets.



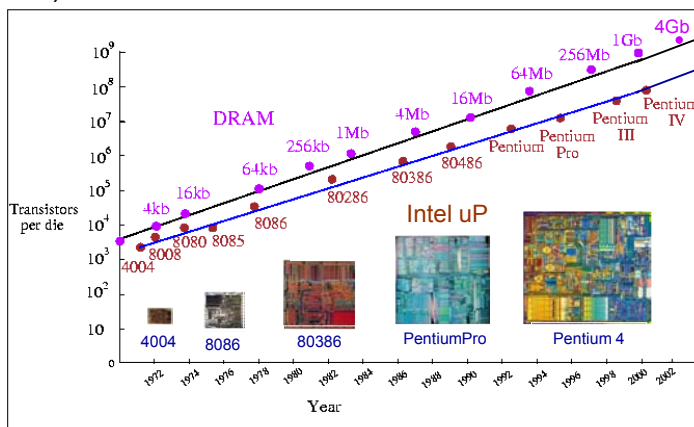
## IC Design Considerations



- Several conflicting considerations:
  - **Design Complexity:** large number of devices/transistors
  - **Performance:** optimization requirements for high performance
  - **Time-to-market:** about a 15% gain for early birds
  - **Cost:** die area, packaging, testing, etc.
  - Others: power, signal integrity (noise, etc), testability, reliability, manufacturability, etc.

## “Moore’s” Law: Driving Technology Advances

- Logic capacity doubles per IC at a regular interval.
- Moore: Logic capacity doubles per IC every two years (1975).
- D. House: Computer performance doubles every 18 months (1975)



# Technology Roadmap for Semiconductors

Year	1997	1999	2002	2005	2008	2011	2014
Technology node ( $\mu m$ )	250	180	130	100	70	50	35
On-chip local clock (GHz)	0.75	1.25	2.1	3.5	6.0	10	16.9
Microprocessor chip size ( $mm^2$ )	300	340	430	520	620	750	901
Microprocessor transistors/chip	11M	21M	76M	200M	520M	1.40B	3.62B
Microprocessor cost/transistor ( $\times 10^{-8}$ USD)	3000	1735	580	255	110	49	22
DRAM bits per chip	256M	1G	4G	16G	64G	256G	1T
Wiring level	6	6-7	7	7-8	8-9	9	10
Supply voltage (V)	1.8-2.5	1.5-1.8	1.2-1.5	0.9-1.2	0.6-0.9	0.5-0.6	0.37-0.42
Power (W)	70	90	130	160	170	175	183

- Source: International Technology Roadmap for Semiconductors (ITRS), Nov. 2002. <http://www.itrs.net/ntsr/pubIntrs.nsf>.
- Deep submicron technology: node (**feature size**)  $< 0.25 \mu m$ .
- Nanometer Technology: node  $< 0.1 \mu m$ .

## Nanometer Design Challenges

- In 2005, feature size  $\approx 0.1 \mu m$ ,  $\mu P$  frequency  $\approx 3.5$  GHz, die size  $\approx 520 mm^2$ ,  $\mu P$  transistor count per chip  $\approx 200M$ , wiring level  $\approx 8$  layers, supply voltage  $\approx 1$  V, power consumption  $\approx 160$  W.
  - **Feature size**  $\downarrow \rightarrow$  sub-wavelength lithography (impacts of process variation)? noise? wire coupling? reliability?
  - **Frequency**  $\uparrow$ , **dimension**  $\uparrow \rightarrow$  interconnect delay? electromagnetic field effects? timing closure?
  - **Chip complexity**  $\uparrow \rightarrow$  large-scale system design methodology?
  - **Supply voltage**  $\downarrow \rightarrow$  signal integrity (noise, IR drop, etc)?
  - **Wiring level**  $\uparrow \rightarrow$  manufacturability? 3D layout?
  - **Power consumption**  $\uparrow \rightarrow$  power & thermal issues?

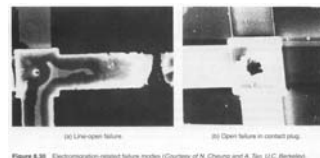
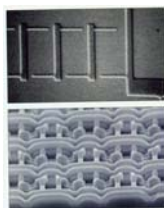
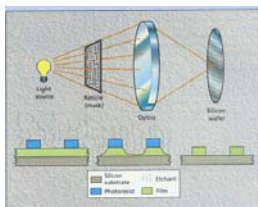
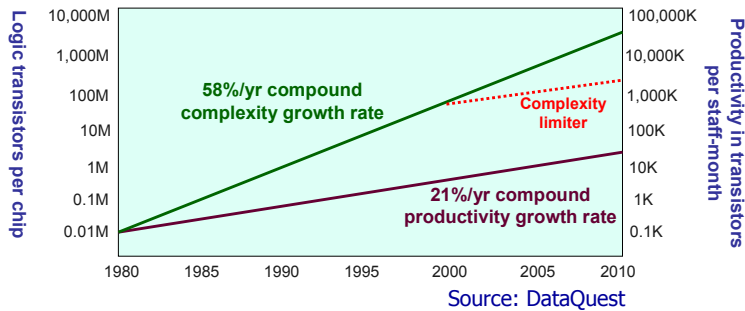


Figure 6.88 Electromigration-related failure modes (Courtesy of N. Cheung and A. Tay (UC Berkeley))

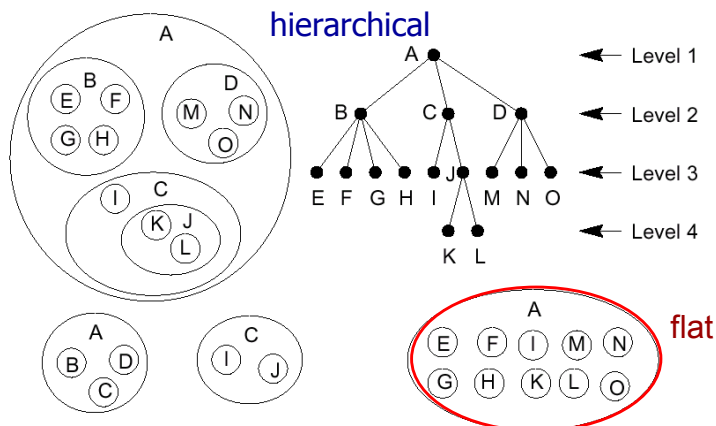
## Design Productivity Crisis



- Human factors may limit design more than technology.
- Keys to solve the productivity crisis: **CAD (tool & methodology)**, hierarchical design, abstraction, IP reuse, platform-based design, etc.

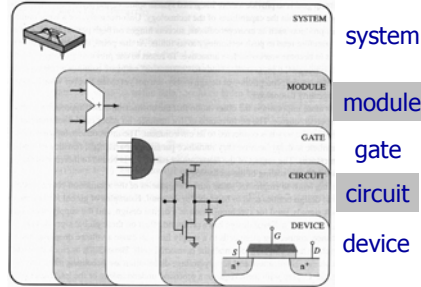
## Hierarchical Design

- **Hierarchy**: something is composed of simpler things.
- Design cannot be done in one step  $\Rightarrow$  partition the design hierarchically.



## Abstraction

- **Abstraction**: when looking at a certain level, you don't need to know all details of the lower levels.

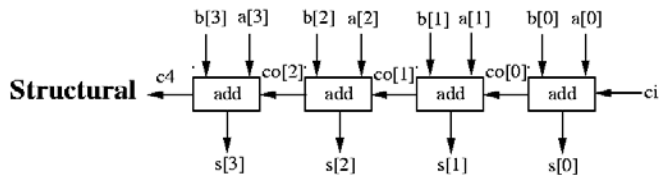


- Design domains:
  - Behavioral: black box view
  - Structural: interconnection of subblocks
  - Physical: layout properties
- Each design domain has its own hierarchy.

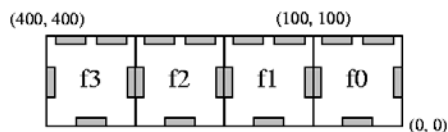
## Three Design Views

### Behavior

```
module add4 (s, c4, ci, a, b);
    input [3:0] a, b;
    input ci;
    output [3:0] s;
    output c4;
    wire [2:0] co;
    add f0 (co[0], s[0], a[0], b[0], ci);
    add f1 (co[1], s[1], a[1], b[1], co[0]);
    add f2 (co[2], s[2], a[2], b[2], co[1]);
    add f3 (c4, s[3], a[3], b[3], co[2]);
endmodule
```

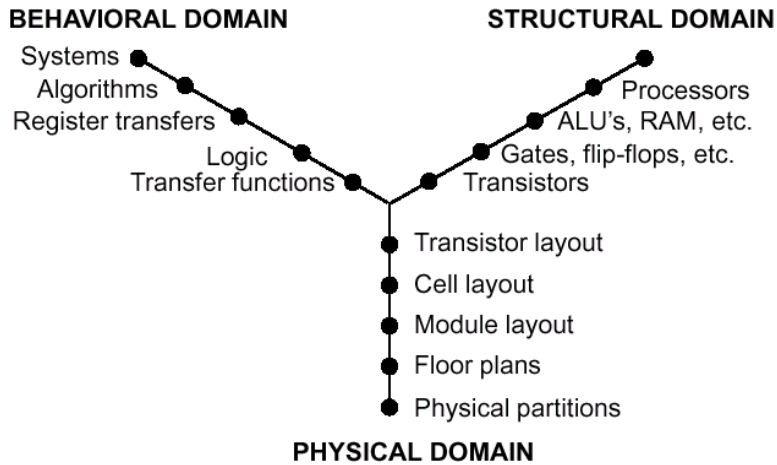


### Physical

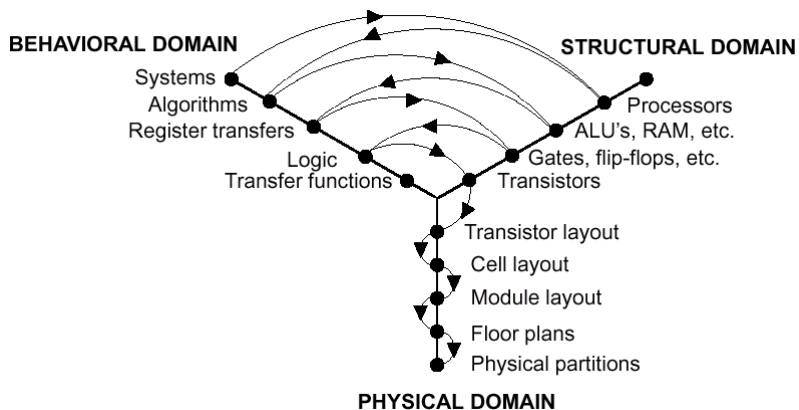




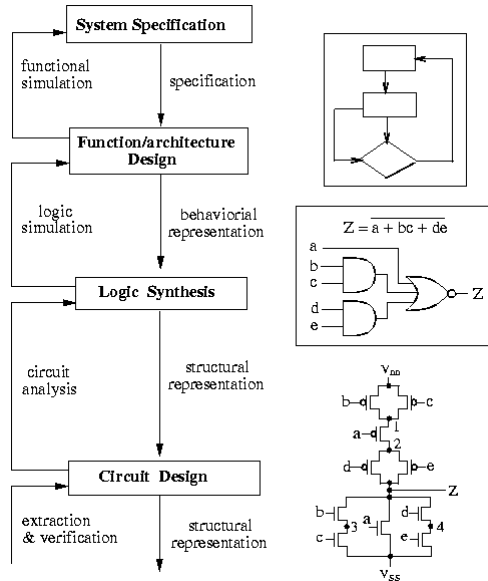
## Gajski's Y-Chart



## Top-Down Structural Design



# Traditional VLSI Design Flow Revisited

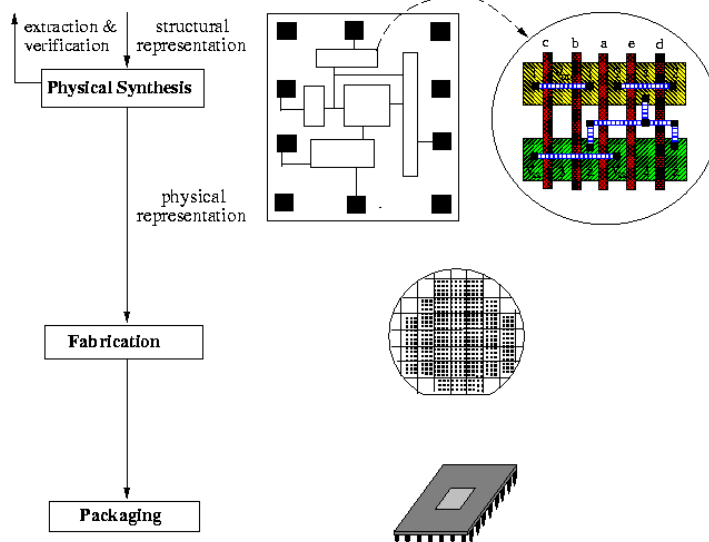


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35

# Traditional VLSI Design Flow Revisited (Cont'd)



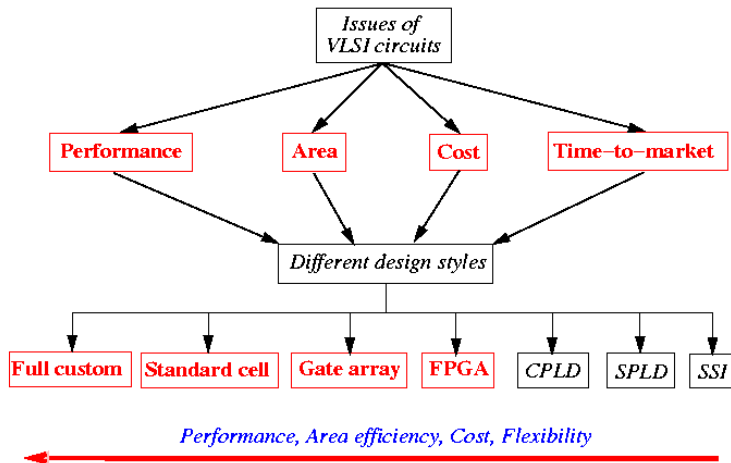
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36

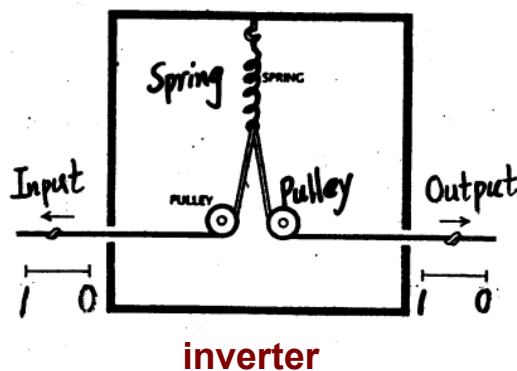
## Design Styles

- Specific design styles shall require specific CAD tools



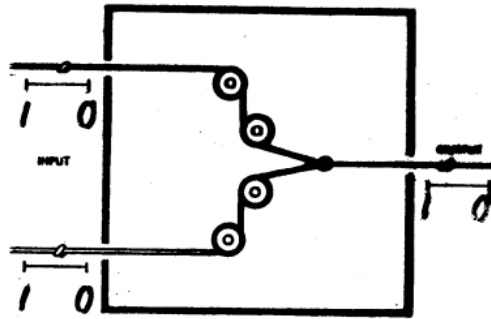
## An Ancient Way of Digital Design (1/3)

- An ancient rope-and-pulley “computer” on the island of Araphul ( $\approx$  A.D. 850).
  - Joke by A. K. Dewdney, “Computer recreations,” *Scientific American*, April 1988.



## An Ancient Way of Digital Design (2/3)

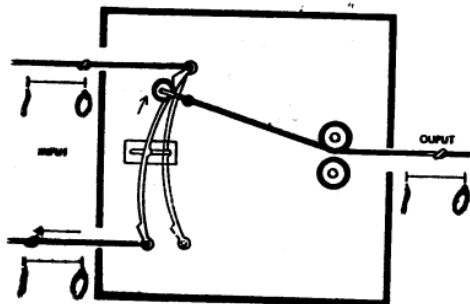
- What is this??



**OR gate**

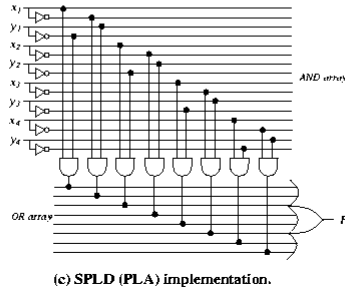
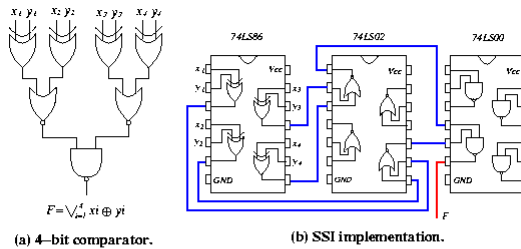
## An Ancient Way of Digital Design (3/3)

- What is this??



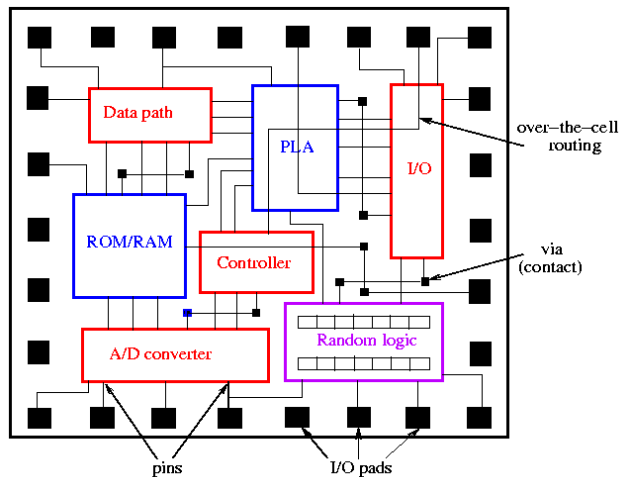
**AND gate**

## SSI/SPLD Design Style



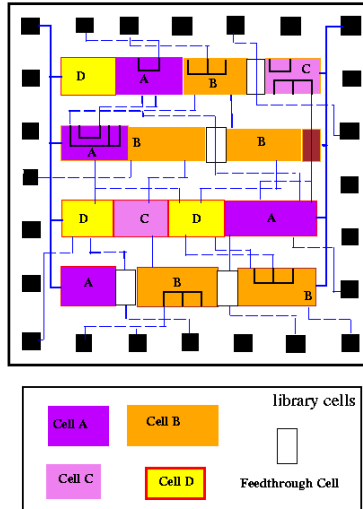
## Full Custom Design Style

- Designers can control the shape of all mask patterns.
- Designers can specify the design up to the level of individual transistors.



## Standard Cell Design Style

- Selects pre-designed cells (of same height) to implement logic

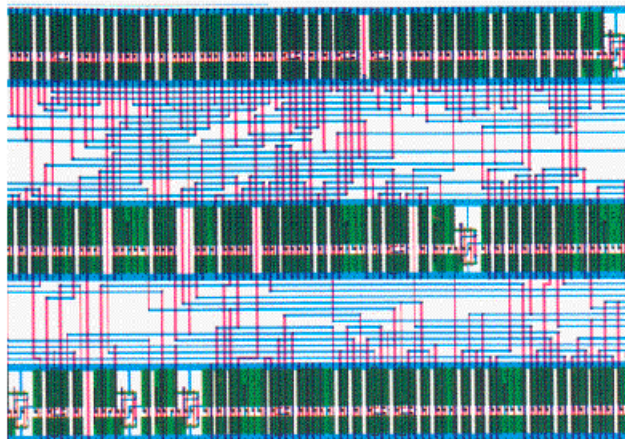


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43

## Standard Cell Example



Courtesy Newton/Pister, UC-Berkeley

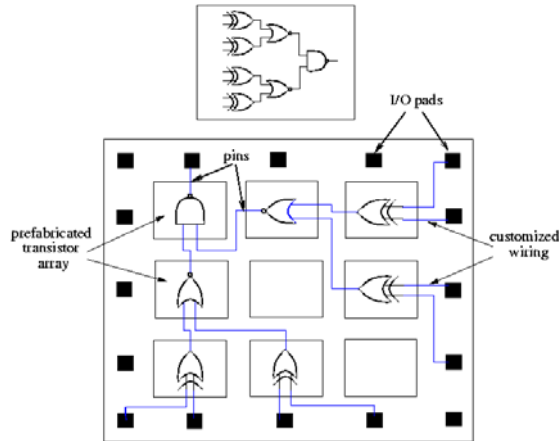
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44

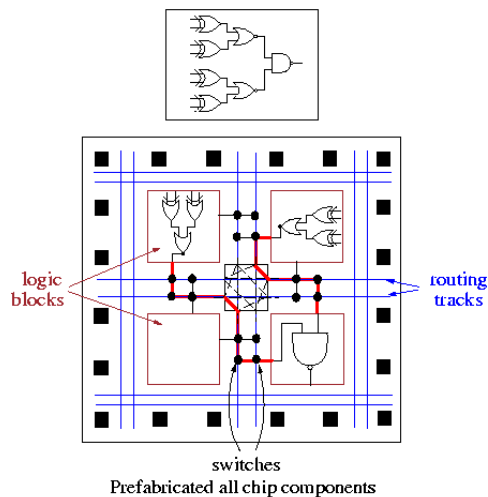
## Gate Array Design Style

- Prefabricates a transistor array
- Needs wiring customization to implement logic

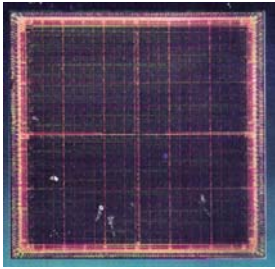


## FPGA Design Style

- Logic and interconnects are both prefabricated.
- Illustrated by a symmetric array-based FPGA

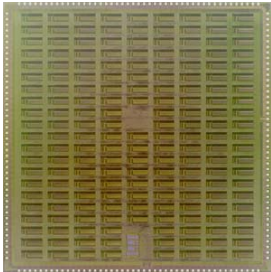


## Array-Based FPGA Example



Lucent Technologies 15K ORCA FPGA, 1995

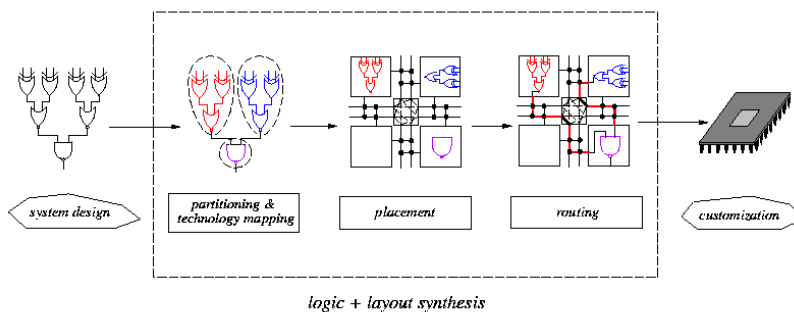
- 0.5  $\mu\text{m}$  3LM CMOS
- 2.45 M Transistors
- 1600 Flip-flops
- 25K bit user RAM
- 320 I/Os



Fujitsu's non-volatile Dynamically Programmable Gate Array (DPGA), 2002

## FPGA Design Process

- Illustrated by a symmetric array-based FPGA
- No fabrication is needed





## Comparisons of Design Styles

	Full custom	Standard cell	Gate array	FPGA	SPLD
Cell size	variable	fixed height*	fixed	fixed	fixed
Cell type	variable	variable	fixed	programmable	programmable
Cell placement	variable	in row	fixed	fixed	fixed
Interconnections	variable	variable	variable	programmable	programmable

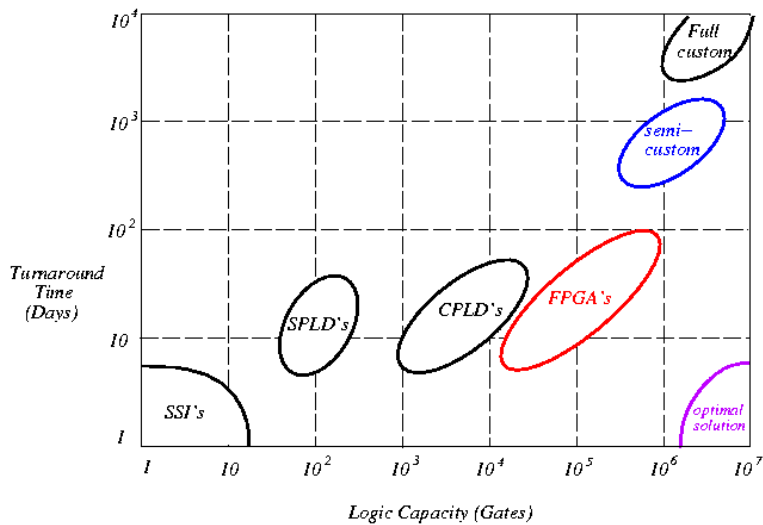
\* Uneven height cells are also used.

## Comparisons of Design Styles

	Full custom	Standard cell	Gate array	FPGA	SPLD
Fabrication time	— — —	— —	+	+++	++
Packing density	+++	++	+	— —	— — —
Unit cost in large quantity	+++	++	+	— —	—
Unit cost in small quantity	— — —	— —	+	+++	++
Easy design and simulation	— — —	— —	—	++	+
Easy design change	— — —	— —	—	++	++
Accuracy of timing simulation	—	—	—	+	++
Chip speed	+++	++	+	—	— —

+ desirable; — not desirable

## Design Style Trade-offs



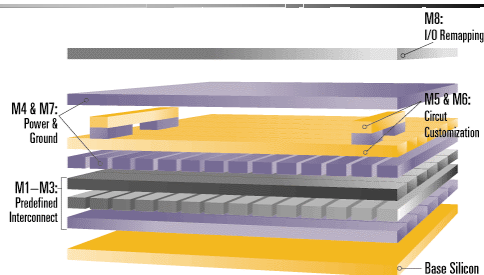
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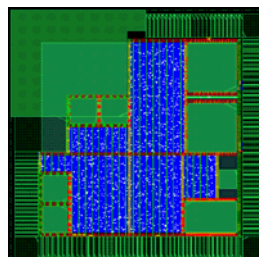
51

## Upcoming: Structured ASIC

- A structured ASIC consists of predefined metal and via layers, as well as a few of them for customization.
- The predefined layers support power distribution and local communications among the building blocks of the device.
- Advantages: fewer masks (lower cost) ; easier physical extraction and analysis.



A structured ASIC (M5 & M6 can be customized)



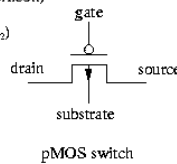
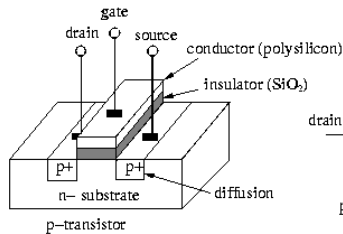
- Green blocks: I/C cells and other hard macro blocks
- Blue area: standard cells
- White points: the spare cells

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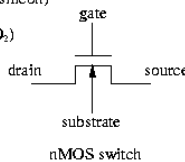
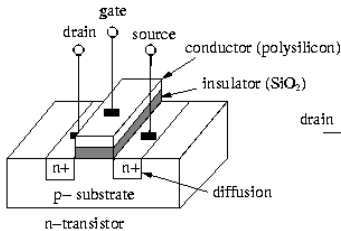
52

# MOS Transistors



- control input: gate
- switch terminals: drain, source (physically equivalent)
- apply zero voltage to gate  $\Rightarrow$  switch ON

**The pMOS switch passes signal "1" well.**

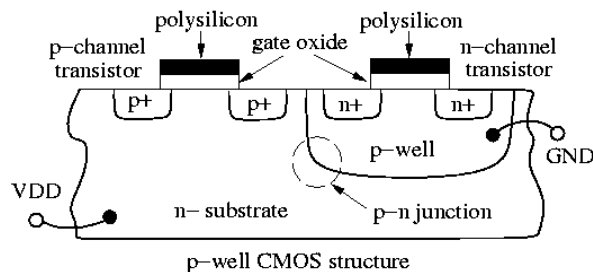


- apply  $>$  threshold voltage to gate  $\Rightarrow$  switch ON

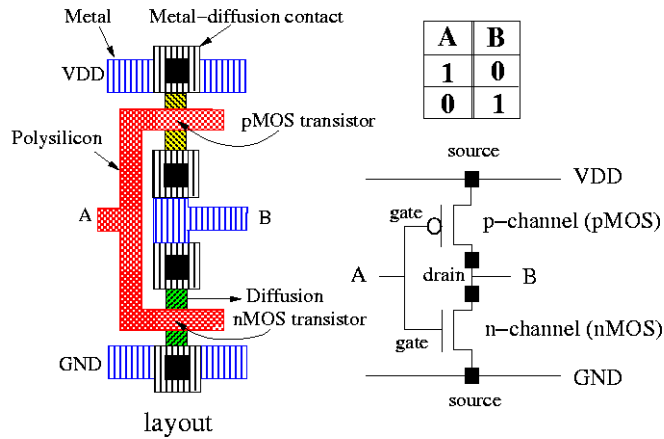
**The nMOS switch passes signal "0" well.**

## Complementary MOS (CMOS)

- The most popular VLSI technology (v.s. BiCMOS, nMOS).
- CMOS uses both *n*-channel and *p*-channel transistors.
- Advantages: lower power dissipation, higher regularity, more reliable performance, higher noise margin, larger fanout, etc.
- Each type of transistor must sit in a material of the complementary type (the reverse-biased diodes prevent unwanted current flow).

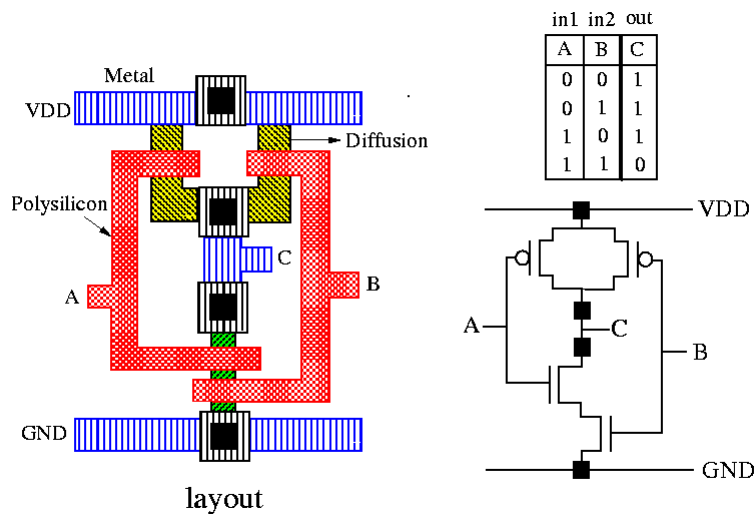


## A CMOS Inverter

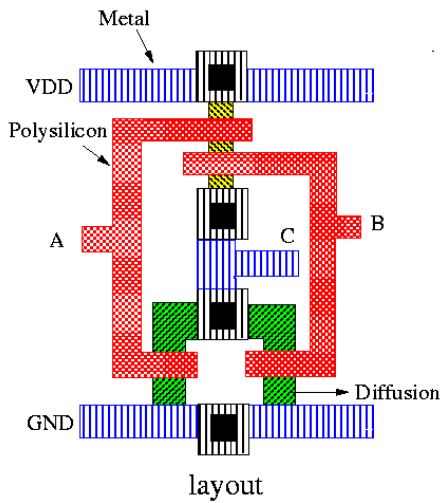


metal 1: blue
  polysilicon: red
  p-diffusion: yellow (p-well: light yellow)
  metal 2: brown
  contact/via: black
  n-diffusion: green (n-well: light green)

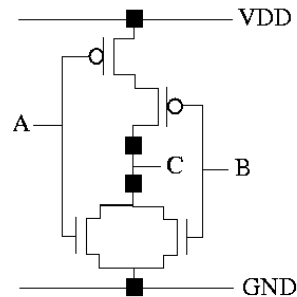
## A CMOS NAND Gate



## A CMOS NOR Gate



A	B	C
0	0	1
0	1	0
1	0	0
1	1	0

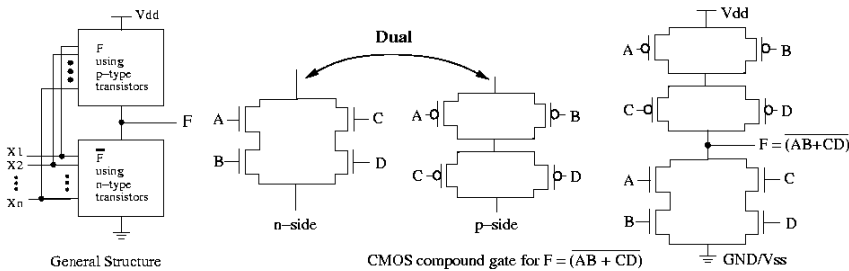


## Basic CMOS Logic Library

Name	Distinctive shape	Algebraic equation	Cost (# of transistors)	Scaled gate delay (ps)
AND		$F=XY$	6	24
OR		$F=X+Y$	6	24
NOT (inverter/repeater)		$F=\overline{X}$	2	10
Buffer (driver/repeater)		$F=X$	4	20
NAND		$F=\overline{XY}$	4	14
NOR		$F=\overline{X+Y}$	4	14
Exclusive-OR (XOR)		$F=X\overline{Y}+\overline{X}Y$ $=X\oplus Y$	14	42

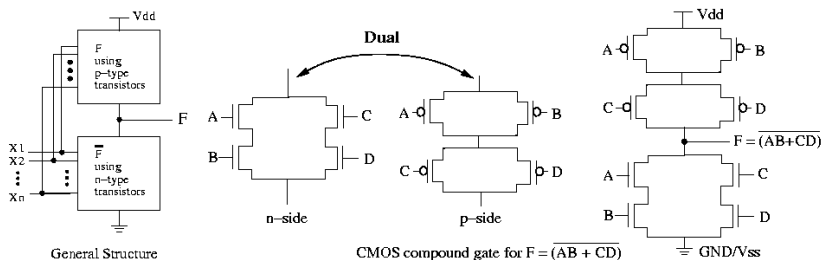
## Construction of Compound Gates

- Example:  $F = \overline{A \cdot B} + C \cdot D$ .
- Step 1 (**n**-network): **Invert**  $F$  to derive  $n$ -network ( $\overline{F} = A \cdot B + C \cdot D$ )
- Step 2 (**n**-network): Make connections of transistors:
  - AND  $\Leftrightarrow$  Series connection
  - OR  $\Leftrightarrow$  Parallel connection



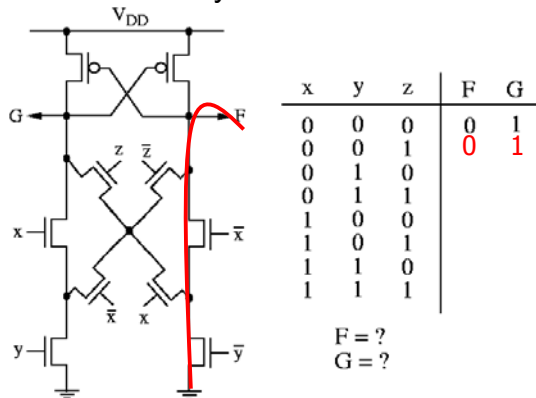
## Construction of Compound Gates (cont'd)

- Step 3 (**p**-network): Expand  $F$  to derive  $p$ -network
  - $(F = \overline{AB + CD} = \overline{AB} \cdot \overline{CD} = (\overline{A} + \overline{B}) \cdot (\overline{C} + \overline{D}))$
  - **each input is inverted**
- Step 4 (**p**-network): Make connections of transistors (same as Step 2).
- Step 5: Connect the  $n$ -network to GND (typically, 0V) and the  $p$ -network to VDD (5V, 3.3V, or 2.5V, etc).



## A Complex CMOS Gate

- The functions realized by the  $n$  and  $p$  networks must be complementary, and one of the networks must conduct for every input combination.
- Duality is not necessary.

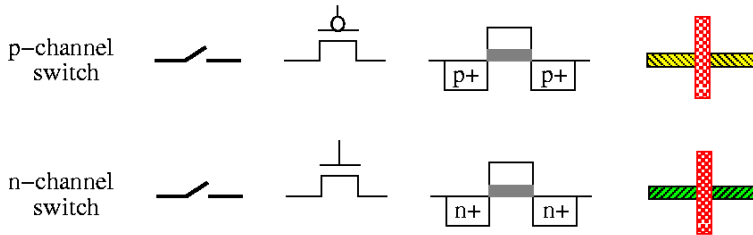


## CMOS Properties

- There is always a path from one supply ( $V_{DD}$  or  $GND$ ) to the output.
- There is never a path from one supply to the other. (This is the basis for the low power dissipation in CMOS--virtually no static power dissipation.)
- There is a momentary drain of current (and thus power consumption) when the gate switches from one state to another.
  - Thus, CMOS circuits have dynamic power dissipation.
  - The amount of power depends on the switching frequency.

## Stick Diagram

- Intermediate representation between the transistor level and the mask (layout) level.
- Gives topological information (identifies different layers and their relationship)
- Assumes that wires have no width.
- Possible to translate stick diagram automatically to layout with correct **design rules**.



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63

## Stick Diagram (cont'd)

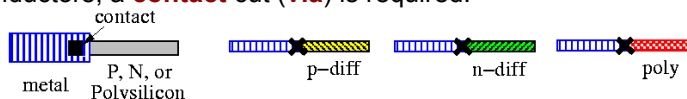
- When the same material (on the same layer) touch or cross, they are connected and belong to the same electrical node.



- When **polysilicon** crosses N or P **diffusion**, an N or P transistor is formed.
  - Polysilicon is drawn on top of diffusion.
  - Diffusion must be drawn connecting the source and the drain.
  - Gate is automatically self-aligned during fabrication.



- When a metal line needs to be connected to one of the other three conductors, a **contact cut (via)** is required.



Unit 1

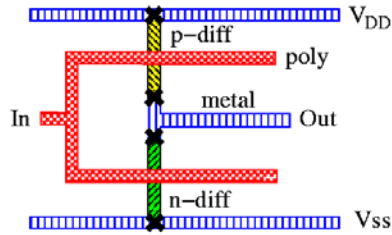
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64

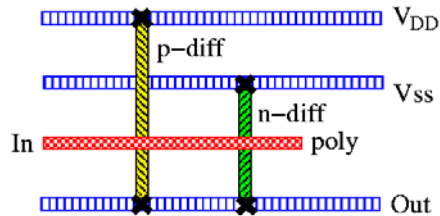


## CMOS Inverter Stick Diagrams

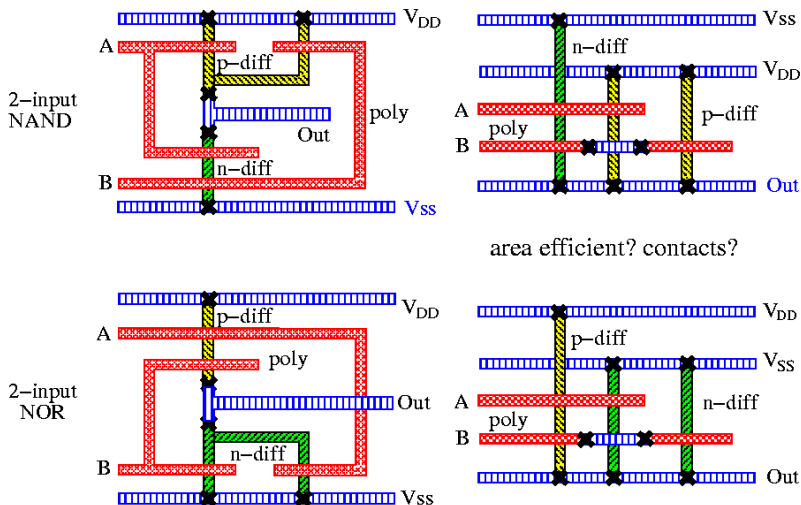
- Basic layout



- More area efficient layout



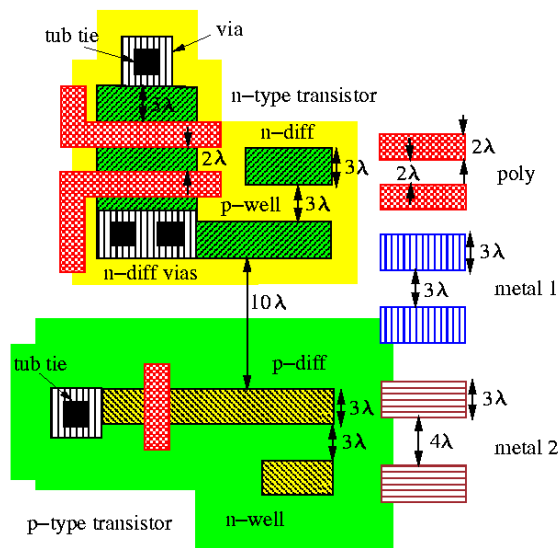
## CMOS NAND/NOR Stick Diagrams



## Design Rules

- Layout rules are used for preparing the masks for fabrication.
- Fabrication processes have inherent limitations in accuracy.
- Design rules specify geometry of masks to optimize yield and reliability (trade-offs: area, yield, reliability).
- Three major rules:
  - **Wire width:** Minimum dimension associated with a given feature.
  - **Wire separation:** Allowable separation.
  - **Contact:** overlap rules.
- Two major approaches:
  - **“Micron” rules:** stated at micron resolution.
  - **$\lambda$  rules:** simplified micron rules with limited **scaling** attributes.
- $\lambda$  may be viewed as the size of minimum feature.
- Design rules represents a tolerance which insures very high probability of correct fabrication (not a hard boundary between correct and incorrect fabrication).
- Design rules are determined by experience.

## SCMOS Design Rules



## MOSIS Layout Design Rules

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- MOSIS design rules (SCMOS rules) are available at <http://www.mosis.org>.
- 3 basic design rules: Wire width, wire separation, contact rule.
- MOSIS design rule examples

R1	Min active area width	3 $\lambda$
R3	Min poly width	2 $\lambda$
R4	Min poly spacing	2 $\lambda$
R5	Min gate extension of poly over active	2 $\lambda$
R8	Min metal width	3 $\lambda$
R9	Min metal spacing	3 $\lambda$
R10	Poly contact size	2 $\lambda$
R11	Min poly contact spacing	2 $\lambda$